











SN54AC00-SP

SCHS367B - OCTOBER 2008-REVISED FEBRUARY 2015

# SN54AC00-SP Radiation Hardened Quad 2 Input NAND Gate

#### **Features**

- 5962R87549:
  - Radiation Hardness Assurance (RHA) up to TID 100 krad (Si)
  - SEL/SEU Immune to 86 MeV
- 5962-87549:
  - Total Ionizing Dose 50 krad (Si)
- 2-V to 6-V V<sub>CC</sub> Operation
- Inputs Accept Voltages to 6 V
- Max t<sub>pd</sub> of 7 ns at 5 V

## **Applications**

- Satellite Payloads
- Satellite Power on Reset Logic
- RHA Known Good Die (KGD) Offering for Space **Hybrids**

### Pin Functions (Each Gate)

INP	INPUTS			
Α	В	Y		
Н	Н	L		
L	Χ	Н		

### **Logic Diagram (Positive Logic)**



## 3 Description

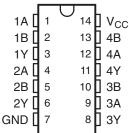
The SN54AC00 device contains four independent 2input NAND gates. Each gate performs the Boolean function of  $Y = \overline{A \cdot B}$  or  $Y = \overline{A} + \overline{B}$  in positive logic.

### Device Information<sup>(1)</sup>

PART NUMBER	PACKAGE	BODY SIZE (NOM)		
	CDIP (14)	5.97 mm × 9.21 mm		
SN54AC00-SP	CFP (14)	6.67 mm × 19.56 mm		
	KGD (0)	Not applicable		

(1) For all available packages, see the orderable addendum at the end of the data sheet.

### J OR W PACKAGE (TOP VIEW)





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1       Features       1         2       Applications       1         3       Description       1         4       Revision History       2         5       Bare Die Information       3         6       Specifications       4         6.1       Absolute Maximum Ratings       4         6.2       Recommended Operating Conditions       4         6.3       Thermal Information       4         6.4       Electrical Characteristics       5	<ul> <li>6.5 Switching Characteristics, V<sub>CC</sub> = 3.3 V</li></ul>
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## 4 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

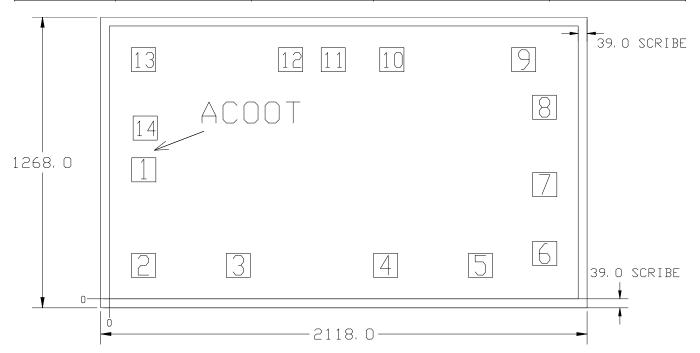
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## 5 Bare Die Information

DIE THICKNESS	BACKSIDE FINISH	BACKSIDE POTENTIAL	BOND PAD METALLIZATION COMPOSITION	BOND PAD THICKNESS
15 mils	Silicon with backgrind	Floating	TiW/AlCu2	15800 nm



### **Bond Pad Coordinates in Microns**

DESCRIPTION	PAD NUMBER	X MIN	Y MIN	X MAX	Y MAX
1A	1	96.3	510.5	201.3	615.5
1B	2	95	94	200	199
1Y	3	508	94	613	199
2A	4	1149	94	1254	199
2B	5	1562	94	1667	199
2Y	6	1841.5	145.5	1946.5	250.5
GND	7	1841.5	445.5	1946.5	550.5
3Y	8	1841	783	1946	888
3A	9	1750.5	991	1855.5	1096
3B	10	1176.5	991	1281.5	1096
4Y	11	921	991	1026	1096
4A	12	736	991	841	1096
4B	13	95	991	200	1096
VCC	14	102.5	692	207.5	797

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### 6 Specifications

### 6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)<sup>(1)</sup>

				MIN	MAX	UNIT
V <sub>CC</sub>	Supply voltage		-	-0.5	7	V
VI	Input voltage (2)		-	-0.5	V <sub>CC</sub> + 0.5	V
Vo	Output voltage (2)		-	-0.5	V <sub>CC</sub> + 0.5	V
I <sub>IK</sub>	Input clamp current	$V_I < 0$ or $V_I > V_{CC}$			±20	mA
lok	Output clamp current	$V_O < 0$ or $V_O > V_{CC}$			±20	mA
Io	Continuous output current	$V_O = 0$ to $V_{CC}$			±50	mA
	Continuous current through	/ <sub>CC</sub> or GND			±200	mA
$T_{J}$	Junction temperature				150	°C
T <sub>stg</sub>	Storage temperature			-65	150	°C

<sup>(1)</sup> Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

### 6.2 Recommended Operating Conditions

			MIN	MAX	UNIT
V <sub>CC</sub>	Supply voltage		2	6	V
		$V_{CC} = 3 V$	2.1		
$V_{IH}$	High-level input voltage	V <sub>CC</sub> = 4.5 V	3.15		V
		V <sub>CC</sub> = 5.5 V	3.85		
		$V_{CC} = 3 V$		0.9	
$V_{IL}$	Low-level input voltage	$V_{CC} = 4.5 \text{ V}$		1.35	V
		V <sub>CC</sub> = 5.5 V		1.65	
$V_{I}$	Input voltage		0	$V_{CC}$	V
$V_{O}$	Output voltage		0	$V_{CC}$	V
		$V_{CC} = 3 V$		12	
$I_{OH}$	High-level output current	V <sub>CC</sub> = 4.5 V		24	mA
		V <sub>CC</sub> = 5.5 V		24	
		V <sub>CC</sub> = 3 V		12	
$I_{OL}$	Low-level output current	V <sub>CC</sub> = 4.5 V		24	mA
		V <sub>CC</sub> = 5.5 V		24	
Δt/Δν	Input transition rise or fall rate			8	ns/V
T <sub>A</sub>	Operating free-air temperature		-55	125	°C

### 6.3 Thermal Information

		SN54A	C00-SP	
	THERMAL METRIC <sup>(1)(2)</sup>	J	W	UNIT
		14 PINS	14 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	83.1	125.4	
R <sub>0</sub> JC(top)	Junction-to-case (top) thermal resistance	26.6	30.85	
$R_{\theta JB}$	Junction-to-board thermal resistance	47.9	43.4	90044
$\Psi_{JT}$	Junction-to-top characterization parameter	N/A	N/A	°C/W
ΨЈВ	Junction-to-board characterization parameter	N/A	N/A	
R <sub>0JC(bot)</sub>	Junction-to-case (bottom) thermal resistance	N/A	N/A	

<sup>(1)</sup> For more information about traditional and new thermal metrics, see the IC Package Thermal Metrics application report, SPRA953.

<sup>(2)</sup> The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

<sup>(2)</sup> The package thermal impedance is calculated in accordance with JESD 51-7 and Mil Std 883 method 1012.1 (see www.JEDEC.org).



## 6.4 Electrical Characteristics

over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED	TEST CONDITIONS	V	T,	<sub>A</sub> = 25°C	MINI MAY		LINUT
PARAMETER	TEST CONDITIONS	V <sub>CC</sub>	MIN	TYP MAX	MIN	MAX	UNIT
		3 V	2.9		2.9		
	$I_{OH} = -50 \mu A$	4.5 V	4.4		4.4		
		5.5 V	5.4		5.4		
$V_{OH}$	I <sub>OH</sub> = -12 mA	3 V	2.56		2.4		V
	1 24 mA	4.5 V	3.86		3.7		
	$I_{OH} = -24 \text{ mA}$	5.5 V	4.86		4.7		
	$I_{OH} = -50 \text{ mA}^{(1)}$	5.5 V			3.85		
	I <sub>OL</sub> = 50 μA	3 V		0.1		0.1	
		4.5 V		0.1		0.1	
		5.5 V		0.1		0.1	
$V_{OL}$	I <sub>OL</sub> = 12 mA	3 V		0.36		0.5	V
		4.5 V	·	0.36		0.5	
	I <sub>OL</sub> = 24 mA	5.5 V	·	0.36		0.5	
	I <sub>OL</sub> = 50 mA <sup>(1)</sup>	5.5 V	·			1.65	
I <sub>I</sub>	V <sub>I</sub> = V <sub>CC</sub> or GND	5.5 V	·	±0.1		±1	μA
Icc	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V	·	4		40	μA
Ci	V <sub>I</sub> = V <sub>CC</sub> or GND	5 V	·	2.6			pF

<sup>(1)</sup> Not more than one output should be tested at a time, and the duration of the test should not exceed 2 ms.



## 6.5 Switching Characteristics, $V_{CC} = 3.3 \text{ V}$

over recommended operating free-air temperature range, V<sub>CC</sub> = 3.3 V ±0.3 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	T	<sub>A</sub> = 25°C		MINI	MAX	UNIT
	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	IVIAA	UNII
t <sub>PLH</sub>	A or B	Y	2	7	9.5	1	11	
t <sub>PHL</sub>	AUIB		ı	1.5	5.5	8	1	9
t <sub>PLH</sub> (KGD only) <sup>(1)</sup>		.,	1	7	9.5	1	11	
t <sub>PHL</sub> (KGD only) <sup>(1)</sup>	A or B	Y	1	5.5	9.5	1	11	ns

<sup>(1)</sup> Specification limits for KGD are based on SMD 5962-8754903

## 6.6 Switching Characteristics, $V_{CC} = 5 \text{ V}$

over recommended operating free-air temperature range,  $V_{CC} = 5 \text{ V} \pm 0.5 \text{ V}$  (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	T,	<sub>A</sub> = 25°C		MIN	MAX	UNIT	
	(INPUT)	(OUTPUT)	MIN	TYP	MAX	IVIIIV	IVIAA	UNII	
t <sub>PLH</sub>	A or D	V	1.5	6	8	1	8.5	20	
t <sub>PHL</sub>	A or B	Y	ı	1.5	4.5	6.5	1	7	ns
t <sub>PLH</sub> (KGD only) <sup>(1)</sup>	A D	Y	1.5	6	8	1	8.5	20	
t <sub>PHL</sub> (KGD only) <sup>(1)</sup>	A or B		1.5	4.5	8	1	8.5	ns	

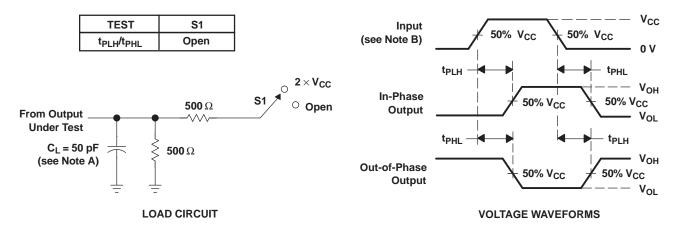
<sup>(1)</sup> Specification limits for KGD are based on SMD 5962-8754903

### 6.7 Operating Characteristics

 $V_{CC} = 5 \text{ V}, T_A = 25^{\circ}\text{C}$ 

	PARAMETER	TEST CONDITIONS	TYP	UNIT
$C_{pd}$	Power dissipation capacitance	$C_L = 50 \text{ pF}, f = 1 \text{ MHz}$	40	pF

### 7 Parameter Measurement Information



NOTES: A.  $C_L$  includes probe and jig capacitance.

- B. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz,  $Z_O$  = 50  $\Omega$ ,  $t_f \leq$  2.5 ns,  $t_f \leq$  2.5 ns.
- C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



## 8 Device and Documentation Support

### 8.1 Trademarks

All trademarks are the property of their respective owners.

### 8.2 Electrostatic Discharge Caution



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

### 8.3 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

## 9 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

# W (R-GDFP-F14)

## CERAMIC DUAL FLATPACK



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. This package can be hermetically sealed with a ceramic lid using glass frit.
- D. Index point is provided on cap for terminal identification only.
- E. Falls within MIL STD 1835 GDFP1-F14



CERAMIC DUAL IN LINE PACKAGE



Images above are just a representation of the package family, actual package may vary. Refer to the product data sheet for package details.

4040083-5/G





CERAMIC DUAL IN LINE PACKAGE



#### NOTES:

- 1. All controlling linear dimensions are in inches. Dimensions in brackets are in millimeters. Any dimension in brackets or parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. This package is hermitically sealed with a ceramic lid using glass frit.
- His package is remitted by sealed with a ceramic its using glass mit.
   Index point is provided on cap for terminal identification only and on press ceramic glass frit seal only.
   Falls within MIL-STD-1835 and GDIP1-T14.



CERAMIC DUAL IN LINE PACKAGE



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